

TEST CELL SOLUTION



Flexible and scalable InStrip handler platform



Modular MEMS options



Diamond_x for low CoO and high parallel test efficiency

MEMS ICs

Highest parallelism and best stimulus quality for MEMS test

Leveraging Leading Test Solutions to Address Today's and Tomorrow's Challenges

- Improve productivity beyond the limits of conventional approaches
- Improve flexibility and agility to react to fluctuating and fast ramp-up demands
- Gain competitive advantage by focusing resources on new, disruptive technologies

OEM Spare Part Supply and Support Services:

- Fastest time to volume and peak productivity
- Highest accuracy for MEMS stimulus and tri-temp control to improve yield
- Industry-leading parallelism and UPH for MEMS test

TEST CELL SOLUTION

1. Highest Parallelism and UPH

- 1.1 Test more than 200 sites in parallel
- 1.2 Better than 99.5 % PTE
- 1.3 Reliable strip handling for higher OEE

2. InStrip Flexible Handler Platform

- 2.1 Modular system supporting wide range of MEMS applications
- 2.2 InCarrier for singulated MEMS test with strip-like parallelism and reliability
- 2.3 Supports smallest packages and WLCSP
- 2.4 Up to 1200 or 2400 I/O, covering widest range of parallelism
- 2.5 -40 °C to +125 °C (Optional: 150 °C) for automotive applications

3. Diamondx Next-Generation SOC ATE

- 3.1 High density Digital, DC, MXSL or RF
- 3.2 IMA scalability for highest parallelism
- 3.3 Lowest Cost of Ownership (CoO) for SOC test

4. Full Ownership of Interfacing and Signal Management

- 4.1 Integrated reference sensors for highest stimulus and temperature accuracy
- 4.2 Sensor stimulus with leading-edge settling times versus competitors
- 4.3 Integrated and pre-validated test cell for fastest time to volume and target OEE/yield

High parallelism MEMS Stimulus Options

InFlip M

For 6DOF Accelerometer and Magnetometer

InGyro M

For 6/9DOF Gyroscope, Accelerometer and Magnetometer

InPressure

For TPMS and absolute pressure sensors up to 20 bar

InBaro

For absolute barometric pressure sensors

InHumid

InBaro upgrade for humidity sensors and 3D environmental MEMS

InPhone

For MEMS microphones

InOptic

For light, UV, IR and reflection sensors



Complete MEMS Test Cell with
Closed-Loop Stimulus and Tri-Temp Control

